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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	BRUEGEMANN, Lutz et al.) Examiner:
Application No.:	10/810,819) unknown
Filing Date:	March 29, 2004) Art Unit:
For:	X-RAY OPTICAL SYSTEM FOR) unknown
	COMBINATORIAL SCREENING OF A)
	SAMPLE LIBRARY)

Atty. Docket No.: P8183US

Commissioner for Patents
Alexandria, VA 22313-1450
U.S.A.

TRANSMITTAL LETTER FOR INFORMATION DISCLOSURE STATEMENT

Please find enclosed:

1. an Information Disclosure Statement under 37 CFR 1.97 (b)(3).
2. Return Postcard

() Please charge my Deposit Account No. 11-1447 in the amount of US \$ to cover the above fees.

- () A check in the amount of US \$ is enclosed.
- () Applicant believes that this submission is timely and that no petition for an extension of time under 37 CFR 1.136(a) is required.
- () Applicant, however, conditionally petitions for such an extension should same be necessary.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. 11-1447.

Respectfully submitted,

Paul Vincent

Dr. Paul Vincent,
Reg. No. 37,461

July 28, 2005

Date

Kohler Schmid Moebus

Patentanwälte

Ruppmannstrasse 27

D-70565 Stuttgart

Germany

Telephone: 49-711-78 47 30

Fax : 49-711-78 00 996

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INFORMATION DISCLOSURE STATEMENT

The undersigned herewith requests the Examiner to consider the art listed in the attached Disclosure Statement (PTO 1449) in examination of the above referenced U.S. patent application.

This submittal is being made under 37 CFR 1.97 (b)(3). No fee is due. If any fees are necessary, please charge same to Account No. 11-1447.

Respectfully submitted,

Paul Vincent

Dr. Paul Vincent
Reg. No. 37,461

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Date

Enclosures:

PTO-Form 1449 (2 pages)

European Search Report and translation of relevant portions thereof

Copies of cited references which are not US patents or publications

Kohler Schmid & Partner

Patentanwälte

Ruppmannstrasse 27

D-70565 Stuttgart

Germany

Telephone: 49-711-78 47 30

Fax : 49-711-78 00 996

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet	1	of	2
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Complete if Known

Application Number	10/810,819
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Filing Date	March 29, 2004
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First Named Inventor	BRUEGEMANN, Lutz
Group Art Unit	

Examiner Name

Attorney Docket Number P8183US

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

Examiner Signature		Date Considered	
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Substitute for form 1449B/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/810,819
				Filing Date	March 29, 2003
				First Named Inventor	BRUEGEMANN, Lutz
				Group Art Unit	
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	P8183US

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s). publisher, city and/or country where published	T
		<p>OMOTE K et al. "A convergent beam parallel detection X-ray diffraction system for characterizing combinatorial epitaxial thin films" Combinatorial and Composition Spread Techniques in Materials and Device Development, San Jose, CA, USA, 01.26.2000, Bd. 3941, Pages 84-91, XP002291973 Proceedings of the SPIE - The International Society for Optical Engineering, 2000, SPIE-Int. Soc. Opt. Eng, USA ISSN: 0277-786X, Fig. 1</p>	
		<p>ISAACS E D ET AL.; "Synchrotron X-Ray Microbeam Diagnostics of Combinatorial Synthesis". Applied Physics Letters, American Institute of Physics. New York, US., Vol. 73, Nr. 13, Pages 1820 - 1822, XP001120660, ISSN: 003-6951, Page 1820, last Par. - Page 1821, Par. 1, Fig. 1</p>	

Examiner Signature		Date Considered	
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